TOSHIBA CCD Linear Image Sensor CCD (Charge Coupled Device)

TCD2724DG-1



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The TCD2724DG-1 is a high sensitive and low dark current 7450 elements \times 3 lines CCD color linear image sensor.

The device contains a row of 7450 elements \times 3 lines photodiodes which provide 24 lines/mm across a A3 size paper. The device is operated by 3.3 V pulse and 10 V power supply.

WDIP22-G-400-2.54

Features

- Number of Image Sensing Elements: 7450 elements × 3 lines
- Image Sensing Element Size: 4.7 μm by 4.7 μm on 4.7 μm center
- Photo Sensing Region: High sensitive PN photodiode
- Clock: 2-phase (3.3 V)
- Power Supply Voltage: 10 V (typ.)
- Distance between Photodiode Array: 18.8 μm (4 lines) R array G array, G array B array
- Internal Circuit: Clamp circuit, Sample and hold circuit, Low input capacitance
- Package: 22 pin CERDIPColor Filter: Red, Green, Blue

ABSOLUTE MAXIMUM RATINGS (Note 1)

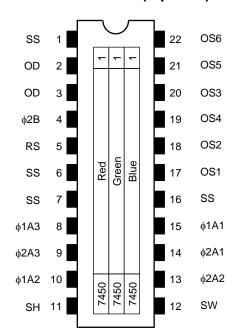
| Characteristics | Symbol | Rating | Unit | |
|--------------------------------|------------------|---------------|------|--|
| Clock pulse voltage | $V_{\phi A}$ | | | |
| Last stage clock pulse voltage | $V_{\phi B}$ | | | |
| Shift pulse voltage | VsH | -0.3 to +8.0 | V | |
| Reset pulse voltage | V _{RS} | | | |
| Switch pulse voltage | Vsw | | | |
| Power supply voltage | Vod | -0.3 to +13.5 | V | |
| Operating temperature | T _{opr} | 0 to 60 | °C | |
| Storage temperature | T _{stg} | -25 to +85 | °C | |

Note 1: All voltages are with respect to SS terminals (ground).

None of the ABSOLUTE MAXIMUM RATINGS must be exceeded, even instantaneously.

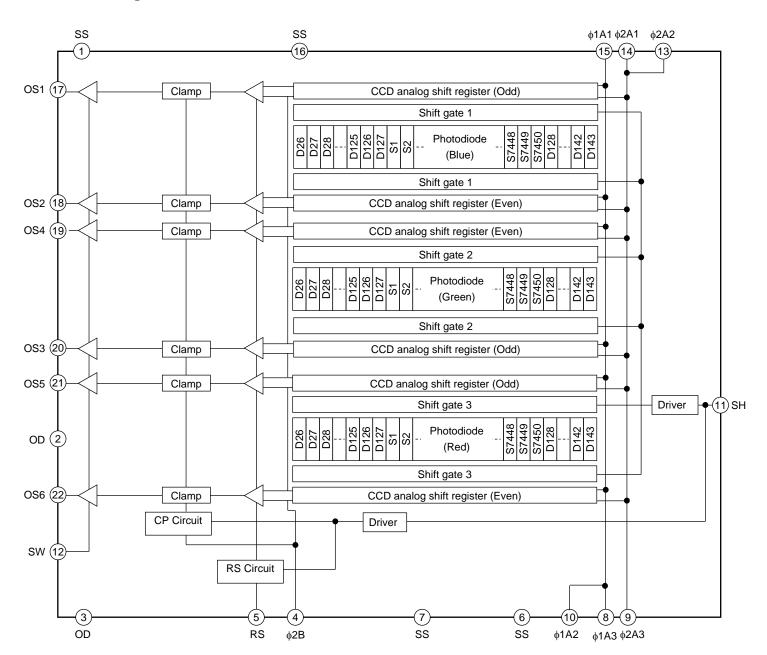
If any one of the ABSOLUTE MAXIMUM RATINGS is exceeded, the electrical characteristics, reliability and life time of the device cannot be guaranteed. If the ABSOLUTE MAXIMUM RATINGS are exceeded, the device can be permanently damaged or degraded. Create a system design in such a manner that any of the ABSOLUTE MAXIMUM RATINGS will not be exceeded under any circumstances.

Pin Connections (top view)





Circuit Diagram



Pin Names

| Pin No. | Symbol | Name | Pin No. | Symbol | Name |
|---------|--------|-------------------------------------|---------|--------|---|
| 1 | SS | Ground | 22 | OS6 | Output signal 6 (Red(Even)) |
| 2 | OD | Power supply | 21 | OS5 | Output signal 5 (Red(Odd)) |
| 3 | OD | Power supply | 20 | OS3 | Output signal 3 (Green(Odd)) |
| 4 | ф2В | Last stage transfer clock (phase 2) | 19 | OS4 | Output signal 4 (Green(Even)) |
| 5 | RS | Reset gate | 18 | OS2 | Output signal 2 (Blue(Even)) |
| 6 | SS | Ground | 17 | OS1 | Output signal 1 (Blue(Odd)) |
| 7 | SS | Ground | 16 | SS | Ground |
| 8 | ф1А3 | Transfer clock 3 (phase 1) | 15 | ф1А1 | Transfer clock 1 (phase 1) |
| 9 | ф2А3 | Transfer clock 3 (phase 2) | 14 | φ2A1 | Transfer clock 1 (phase 2) |
| 10 | φ1A2 | Transfer clock 2 (phase 1) | 13 | φ2A2 | Transfer clock 2 (phase 2) |
| 11 | SH | Shift gate | 12 | SW | Switch gate (Sample and hold output select) |



Optical/Electrical Characteristics

Ta = 25°C, VoD = 10 V, V $_{\phi}$ = VRS = VSH = 3.3 V (pulse), f $_{\phi}$ = 1.0 MHz, tint (integration time) = 10 ms, light source = A light source + CM500S (t = 1.0 mm)

| Characteristics | | Symbol | Min | Тур. | Max | Unit | Note | |
|--|-------|----------------|------|------|------|--------|--------------|--|
| | Red | R _R | 9.0 | 12.8 | 16.6 | | | |
| Sensitivity | Green | RG | 10.5 | 15.0 | 19.5 | | | |
| Enable sample and hold | Blue | R _B | 3.6 | 5.2 | 6.8 | V/lx⋅s | (1) (0) | |
| On and the state of | Red | R _R | 10.0 | 14.3 | 18.6 | V/IX·S | (Note 2) | |
| Sensitivity | Green | RG | 11.8 | 16.9 | 22.0 | | | |
| Disable sample and hold | Blue | R _B | 4.0 | 5.8 | 7.5 | | | |
| Photo response non uniformity | | PRNU (1) | _ | 5 | 20 | % | (Note 3) | |
| | | PRNU (3) | _ | 3 | 12 | mV | (Note 4) | |
| Saturation output voltage | | Vsat | 1.2 | 1.8 | _ | V | (Note 5) | |
| Saturation exposure | | SE | 0.05 | 0.1 | _ | lx⋅s | (Note 6) | |
| Dark signal voltage | | VDRK | _ | 0.5 | 6 | mV | (Note 7) | |
| Dark signal non uniformity | | DSNU | _ | 10 | 12 | mV | (Note 8) | |
| DC power dissipation | | PD | _ | 700 | 1050 | mW | _ | |
| Total transfer efficiency | | TTE | 92 | 97 | _ | % | _ | |
| Output impedance | | ZO | _ | 0.2 | 0.5 | kΩ | _ | |
| DC output signal voltage | | Vos | 3.7 | 5.2 | 6.7 | V | (Note 9) | |
| Random noise (Enable sample and hold) | | | _ | 1.4 | _ | >/ | (N = 1 = 40) | |
| Random noise (Disable sample and hold) | | $N_{D\sigma}$ | _ | 1.1 | _ | mV | (Note 10) | |

Note 2: Sensitivity is defined for each color of signal outputs average when the photosensitive surface is applied with the light of uniform illumination and uniform color temperature.

Note 3: PRNU (1) is defined for each color on a single chip by the expressions below when the photosensitive surface is applied with the light of uniform illumination and uniform color temperature, where measured approximately 600 mV of signal output.

PRNU (1) =
$$\frac{\Delta X}{\overline{X}} \times 100$$
 (%)

 \overline{X} : Average of total signal outputs

 ΔX : The maximum deviation from \overline{X}

Note 4: PRNU (3) is defined as the maximum voltage with next pixel, where measured approximately 50 mV of signal output.

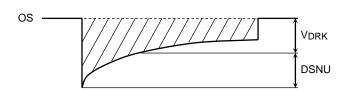
Note 5: VSAT is defined as the minimum saturation output voltage of all effective pixels.

Note 6: Definition of SE:

$$SE = \frac{V_{SAT}}{R_G}$$

Note 7: VDRK is defined as average dark signal voltage of all effective pixels.

Note 8: DSNU is defined by the difference between average value (VDRK) and the maximum value of the dark voltage.

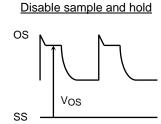




Note 9: DC output signal voltage is defined as follows.

Video signal with sample and hold represents the dummy outputs period.

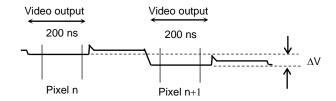
OS Vos



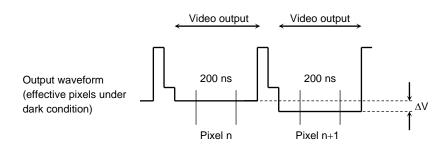
Note 10: Random noise is defined as the standard deviation (sigma) of the output level difference between two adjacent effective pixels under no illumination (i.e. dark condition) calculated by the following procedure.

Enable sample and hold

Output waveform (effective pixels under dark condition)



Disable sample and hold



- 1) Two adjacent pixels (pixel n and n+1) in one reading are fixed as measurement points.
- 2) Each of the output levels at video output periods averaged over 200 ns period to get V(n) and V(n+1).
- 3) V(n+1) is subtracted from V(n) to get ΔV .

$$\Delta V = V(n) - V(n{+}1)$$

4) The standard deviation of ΔV is calculated after procedure 2) and 3) are repeated 30 times (30 readings).

$$\overline{\Delta V} = \frac{1}{30} \sum_{i=1}^{30} \! \left| \Delta Vi \right|$$

$$\sigma = \sqrt{\frac{1}{30} \sum_{i=1}^{30} \! \! \left(\!\! \left| \Delta V i \right| \! - \! \overline{\Delta V} \right)^{\! 2}}$$

- 5) Procedure 2), 3) and 4) are repeated 10 times to get sigma value.
- 6) 10 sigma values are averaged.

$$\overline{\sigma} = \frac{1}{10} \sum_{j=1}^{10} \sigma_j$$

7) $\bar{\sigma}$ value calculated using the above procedure is observed $\sqrt{2}$ times larger than that measured relative to the ground level. So we specify the random noise as follows.

$$ND_{\sigma} = \frac{1}{\sqrt{2}}\bar{\sigma}$$



Recommended Operating Conditions (Ta = 25°C)

For best performance, the device should be used within the Recommended Operating Conditions.

| Characteristics | | Symbol | Min | Тур. | Max | Unit |
|------------------------|-----------|----------------------------------|-----|------|------|------|
| Clock pulse voltage | "H" level | V _{ϕ1A} | 3.1 | 3.3 | 5.5 | V |
| Clock pulse voltage | "L" level | $V_{\phi 2A}$ | 0 | 0 | 0.1 | |
| Last stage clock pulse | "H" level | Vian | 3.1 | 3.3 | 5.5 | V |
| voltage | "L" level | V _{ф2B} | 0 | 0 | 0.1 | |
| Shift pulse voltage | "H" level | VsH | 3.1 | 3.3 | 5.5 | V |
| | "L" level | VSH | 0 | 0 | 0.1 | |
| Poset pulse voltage | "H" level | \/po | 3.1 | 3.3 | 5.5 | V |
| Reset pulse voltage | "L" level | VRS | 0 | 0 | 0.1 | V |
| Switch pulse voltage | "H" level | Vou | 3.1 | 3.3 | 5.5 | V |
| | "L" level | V _{SW} | 0 | 0 | 0.1 | V |
| Power supply voltage | | V _{OD} | 9.5 | 10.0 | 10.5 | ٧ |

Clock Characteristics (Ta = 25°C)

For best performance, the device should be used within the Recommended Operating Conditions.

| Characteristics | Symbol | Min | Тур. | Max | Unit |
|------------------------------|---------------|-----|------|------|------|
| Clock pulse frequency | f_{φ} | 1.0 | 1.0 | 35.0 | MHz |
| Reset pulse frequency | fRS | 1.0 | 1.0 | 35.0 | MHz |
| Clock capacitance (Note 11) | СфА | | 65 | | pF |
| Last stage clock capacitance | $C_{\phi B}$ | | 7 | | pF |
| Shift gate capacitance | Csh | | 20 | | pF |
| Reset gate capacitance | CRS | | 7 | | pF |

Note 11: VOD = 10 V, Input capacitance per a pin.

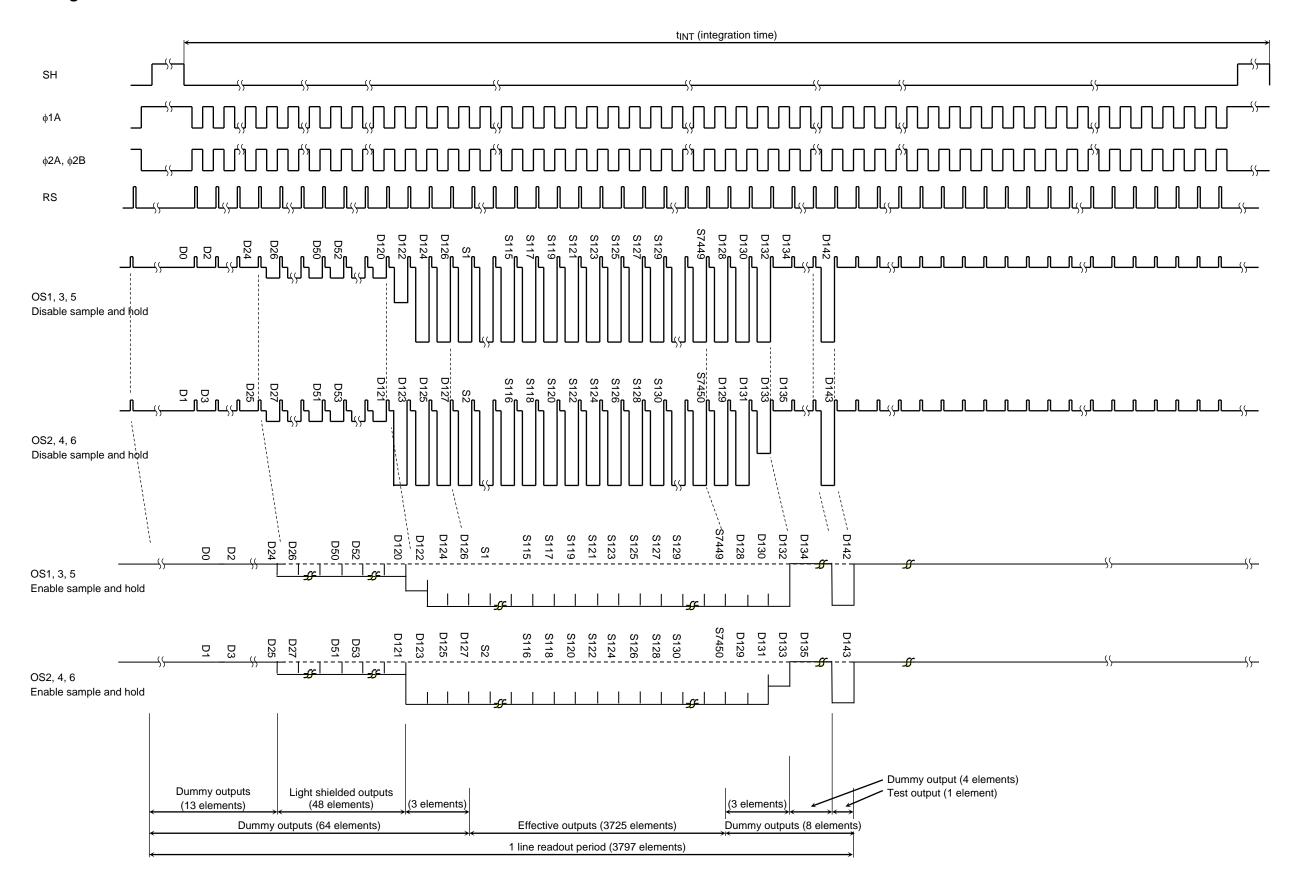
Mode Select (Selection Sample and Hold)

| Mode | SW |
|-------------------------|-----|
| Enable sample and hold | "H" |
| Disable sample and hold | "L" |

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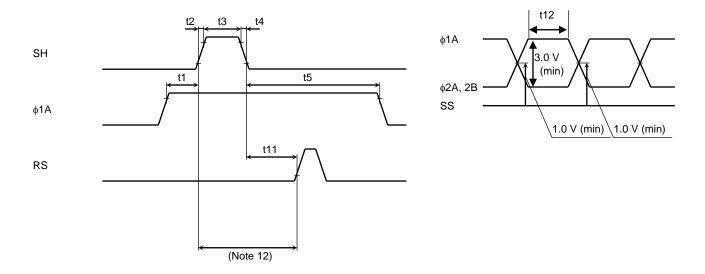


Timing Chart 1

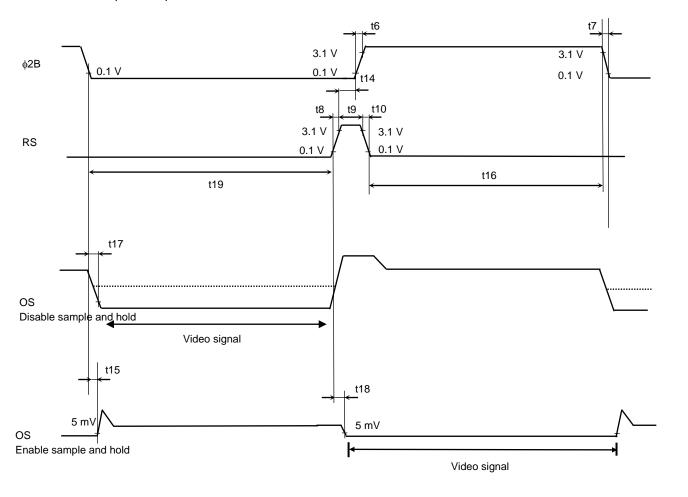




Timing Requirements



Note 12: Keep the RS pin "L" level.





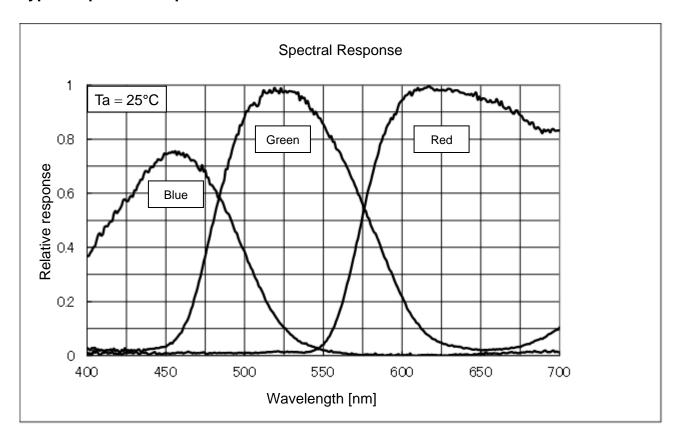
| Characteristics | Symbol | Min | Typ. (Note 13) | Max | Unit |
|--------------------------------|---------|------|-------------------|-----|------|
| Dulga timing of CLL and 14.0 | t1 | 120 | 1000 | _ | ns |
| Pulse timing of SH and φ1A | t5 | 1000 | 1200 | _ | ns |
| SH pulse rise time, fall time | t2, t4 | 0 | 50 | _ | ns |
| SH pulse width | t3 | 2000 | 5000 | _ | ns |
| φ2B pulse rise time, fall time | t6, t7 | 0 | 50 | _ | ns |
| RS pulse rise time, fall time | t8, t10 | 0 | 20 | _ | ns |
| RS pulse width | t9 | 6 | 100 | _ | ns |
| Pulse timing of SH and RS | t11 | 500 | _ | _ | ns |
| φ1A, φ2A pulse width | t12 | 7 | 100 | _ | ns |
| | t14 | 0 | 0 | _ | ns |
| Pulse timing of φ2B and RS | t16 | 6 | 100 | _ | ns |
| | t19 | 8 | 100 | _ | ns |
| Video data delay time | t17 | | 7 | _ | ns |
| Video data delay time | t18 | | 7 | | nc |
| Enable sample and hold | 110 | | / | | ns |
| φ2B pulse timing of OS | t15 | _ | 0 | _ | ns |

Note 13: Measured with fRS = 1 MHz.

8



Typical Spectral Response





Cautions

1. Electrostatic Breakdown

Store in shorting clip or in conductive foam to avoid electrostatic breakdown.

CCD Image Sensor is protected against static electricity, but inferior puncture mode device due to static electricity is sometimes detected. In handing the device, it is necessary to execute the following static electricity preventive measures, in order to prevent the trouble rate increase of the manufacturing system due to static electricity.

- Prevent the generation of static electricity due to friction by making the work with bare hands or by putting a. on cotton gloves and non-charging working clothes.
- Discharge the static electricity by providing earth plate or earth wire on the floor, door or stand of the work b.
- Ground the tools such as soldering iron, radio cutting pliers of or pincer. c.
- lonized air is recommended for discharge when handling CCD image sensors.

It is not necessarily required to execute all precaution items for static electricity.

It is all right to mitigate the precautions by confirming that the trouble rate within the prescribed range.

2. Window Glass

The dust and stain on the glass window of the package degrade optical performance of CCD sensor. Keep the glass window clean by saturating a cotton swab in alcohol and lightly wiping the surface, and allow the glass to dry, by blowing with filtered dry N2. Care should be taken to avoid mechanical or thermal shock because the glass window is easily to damage.

3. Incident Light

CCD sensor is sensitive to infrared light. Note that infrared light component degrades resolution and PRNU of CCD sensor.

Mounting on a PCB

This package is sensitive to mechanical stress.

TOSHIBA recommends using IC inserters for mounting, instead of using lead forming equipment. Since this package is not strong against mechanical stress, you should not reform the lead frame. We recommend to use an IC-inserter when you assemble to PCB.

Soldering

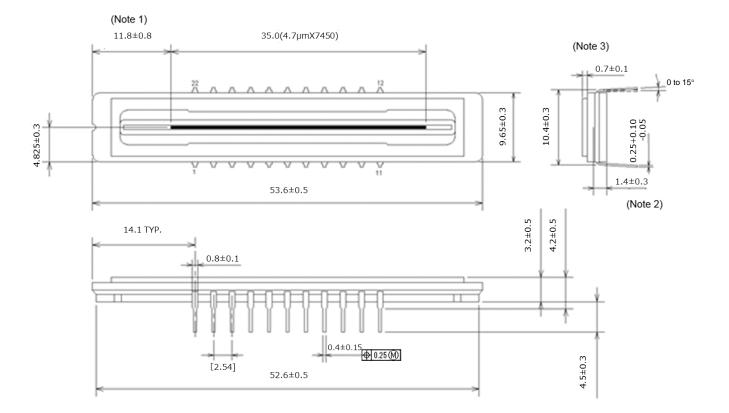
Soldering by the solder flow method cannot be guaranteed because this method may have deleterious effects on prevention of window glass soiling and heat resistance.

Using a soldering iron, complete soldering within three seconds for lead temperatures of up to 350°C.



Package Dimensions

WDIP22-G-400-2.54



Unit: mm

Note 1: Distance between the edge of the package and the first pixel (S1)

Note 2: Distance between the top of chip and bottom of the package

Note 3: Glass thickness (n = 1.5)



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